

INFORMATION DISCLOSURE STATEMENT PTO-1441 O I P E	Atty. Docket No.: 030865	Serial No.: 10/619,192
	Applicants: Mamoru NAKASUJI et al.	
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U.S. PATENT DOCUMENTS

Examiner Initial	Document Type	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
KN	AA	6,411,377	Noguchi et al.	06/25/2002	356	237.4	07/28/1999
KN	AB	6,593,152	Nakasuji et al.	07/15/2003	438	14	11/02/2001
KN	AC	5,892,224	Nakasuji	04/06/1999	250	310	05/09/1997, See page 1 in the spec.
	AD						
	AE						

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Translation (Yes or No)
	AF			
	AG			
	AH			
	AI			
	AJ			

OTHER DOCUMENTS

<u>KN</u>	AK	Shinada, H. et al. "High Speed and Large-Current Electron Optics for Wafer Inspection", Proceedings LSI Testing Symposium/2000 Conference Minutes, pp. 151-156 (English Translation is enclosed (Marked-up Portion Only)., Also see the page 1 in the spec.)
Examiner	<u>lul</u>	Date Considered 10-07-06